Empirical analysis of software-induced failure events in the nuclear industry

Fan CF, Yih S, Tseng WH, Chen WC.
Safety science
2013; 57:118-128

ARTICLE IDENTIFIERS
DOI: 10.1016/j.ssci.2013.02.001
PMID: unavailable
PMCID: not available

JOURNAL IDENTIFIERS
LCCN: 91640944
pISSN: 0925-7535
eISSN: 1879-1042
OCLC ID: 23966897
CONS ID: sn 91-38208
US National Library of Medicine ID: 9114980